Abstract

A list of waveforms is received (the list being one that is to be driven to or received from a pin of a device under test, and each waveform in the list being associated with a weight). For each of at least two waveforms in the list, a number of test sample points lost by masking the waveform with a particular parent waveform in a child-parent waveform map is calculated. The number of lost test sample points is determined by 1) a difference in the number of test sample points in the waveform and the number of test sample points in the particular parent waveform, and 2) the weight associated with the waveform. In response to the calculations, a waveform masking is implemented such that the implemented waveform masking results in fewer lost test sample points than another waveform masking.